Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	1	
10/808,560	OHNISHI, MAKOTO		
Examiner	Art Unit		
Gopal C. Ray	2111		

SEARCHED					
Class	Subclass	Date	Examiner		
710	305,313,3 00,33,110, 316	4/20/2006	GCR		
715	735	4/20/2006	GCR		
365	189.04	4/20/2006	GCR		
711	155,203	4/20/2006	GCR		
709	223,238	4/20/2006	GCR		
709	208,213	4/20/2006	GCR		
709	253	4/20/2006	GCR		
370	434,230	4/20/2006	GCR		
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370	244,464	4/20/2006	GCR		
370	492,421	4/20/2006	GCR		
710	305	4/20/2006	GCR		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
PGPUB text search - see interfernce search printout		4/20/2006	GCR		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	4/20/2006	GCR
EAST: USPT (see search history printouts)	4/20/2006	GCR
NPL: IEEE Xplore (see search history printouts)	4/20/2006	GCR
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